Integrated Device Technology, Inc.
6024 Silver Creek Valley Road, San Jose, CA - 95138

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: **PA-1109-01** DATE: **Sept. 27, 2011**

Product Affected: See Listing in Attachment 1

Date Effective: **Sept. 27, 2011**

MEANS OF DISTINGUISHING CHANGED DEVICES:

- ☐ Product Mark
- ☐ Back Mark
- ■ Date Code **Date Code ≥ 1137**
- ☐ Other

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Attachment:: ■ Yes ☐ No

Samples: Available upon request

DESCRIPTION AND PURPOSE OF CHANGE:

- ☐ Die Technology
- ☐ Wafer Fabrication Process
- ☐ Assembly Process
- ☐ Equipment
- ☐ Material
- ☐ Testing
- ☐ Manufacturing Site
- ■ Data Sheet
- ☐ Other

This notification is to advise our customers that IDT has updated datasheet and test limits for device types IDT70P265L65BYGI, IDT70P255L65BYGI and IDT70P245L65BYGI. The test specifications limits have been tightened for tAVD and tAVDS test parameters.

This is a data sheet enhancement and there is no change to die.

RELIABILITY/QUALIFICATION SUMMARY:

There is no change to die technology/process.

CUSTOMER ACKNOWLEDGMENT OF RECEIPT:

IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.
IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: _____ ☐ ***Approval for shipments prior to effective date.***

Name/Date: _____ E-Mail Address: _____

Title: _____ Phone# /Fax# : _____

CUSTOMER COMMENTS: _____

IDT ACKNOWLEDGMENT OF RECEIPT:

RECD. BY: _____ DATE: _____

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PRODUCT/PROCESS CHANGE NOTICE (PCN)

ATTACHMENT 1 - PCN #: PA-1109-01

PCN Type: Data Sheet Change

Data Sheet Change Yes

Detail of Change

This notification is to advise our customers that IDT has updated datasheet and test limits for device types IDT70P265L65BYGI, IDT70P255L65BYGI and IDT70P245L65BYGI. The test specifications limits have been tightened for tAVD and tAVDS test parameters.

This is a data sheet enhancement and there is no change to die.

The test specifications limit have been changed as follow:

From:
tAVD low pulse = 15ns
tAVDS address set-up to ADV rising edge = 15ns

To:
tAVD low pulse = 7ns
tAVDS address set-up to ADV rising edge = 7ns

Revised data sheet is available on IDT Web Site.

AFFECTED PRODUCTS:

IDT70P265L65BYGI
IDT70P255L65BYGI
IDT70P245L65BYGI